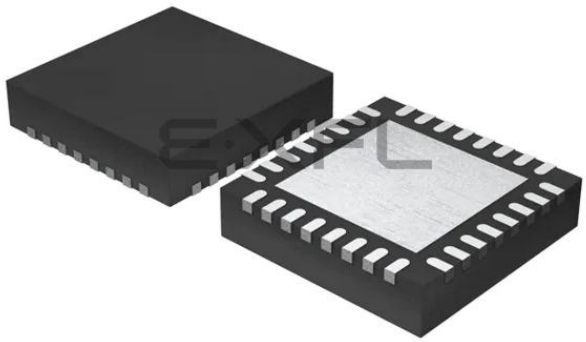

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	24
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.8V
Data Converters	A/D 12bit SAR; D/A 12bit
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TJ)
Mounting Type	Surface Mount
Package / Case	32-WFQFN Exposed Pad
Supplier Device Package	32-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm32tg11b140f64im32-ar

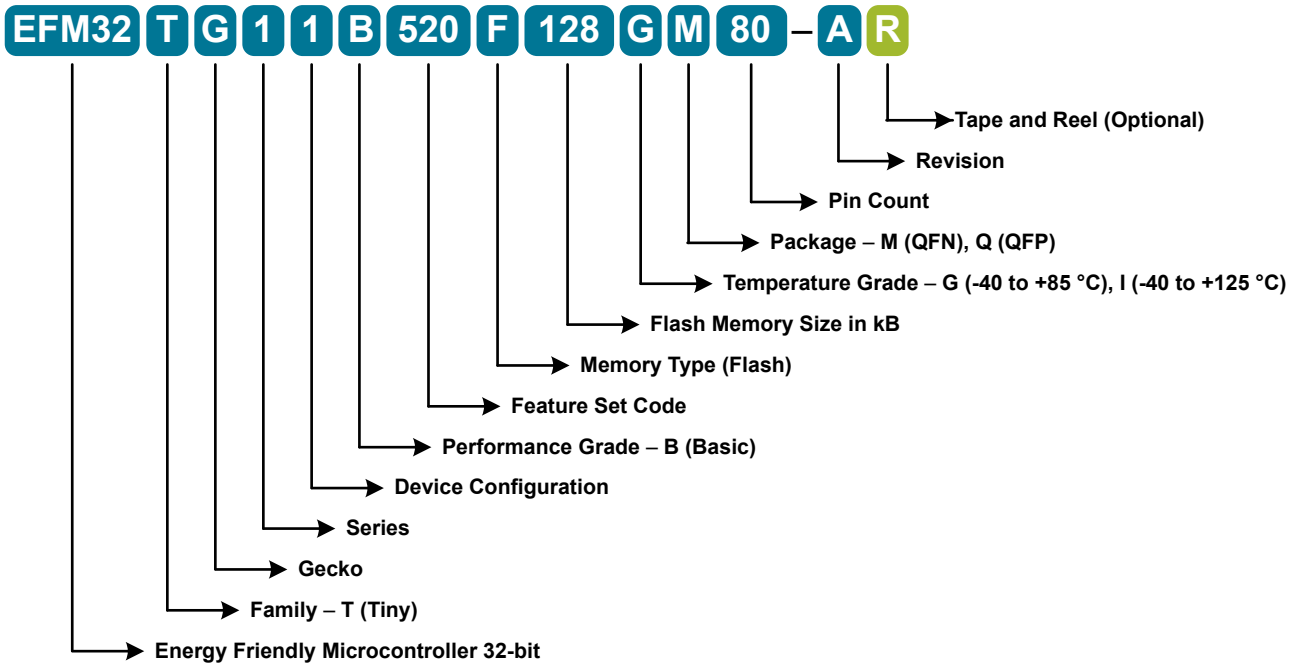

Figure 2.1. Ordering Code Key

3.6.5 Controller Area Network (CAN)

The CAN peripheral provides support for communication at up to 1 Mbps over CAN protocol version 2.0 part A and B. It includes 32 message objects with independent identifier masks and retains message RAM in EM2. Automatic retransmittion may be disabled in order to support Time Triggered CAN applications.

3.6.6 Peripheral Reflex System (PRS)

The Peripheral Reflex System provides a communication network between different peripheral modules without software involvement. Peripheral modules producing Reflex signals are called producers. The PRS routes Reflex signals from producers to consumer peripherals which in turn perform actions in response. Edge triggers and other functionality such as simple logic operations (AND, OR, NOT) can be applied by the PRS to the signals. The PRS allows peripheral to act autonomously without waking the MCU core, saving power.

3.6.7 Low Energy Sensor Interface (LESENSE)

The Low Energy Sensor Interface LESENSE™ is a highly configurable sensor interface with support for up to 16 individually configurable sensors. By controlling the analog comparators, ADC, and DAC, LESENSE is capable of supporting a wide range of sensors and measurement schemes, and can for instance measure LC sensors, resistive sensors and capacitive sensors. LESENSE also includes a programmable finite state machine which enables simple processing of measurement results without CPU intervention. LESENSE is available in energy mode EM2, in addition to EM0 and EM1, making it ideal for sensor monitoring in applications with a strict energy budget.

3.7 Security Features

3.7.1 GPCRC (General Purpose Cyclic Redundancy Check)

The GPCRC module implements a Cyclic Redundancy Check (CRC) function. It supports both 32-bit and 16-bit polynomials. The supported 32-bit polynomial is 0x04C11DB7 (IEEE 802.3), while the 16-bit polynomial can be programmed to any value, depending on the needs of the application.

3.7.2 Crypto Accelerator (CRYPTO)

The Crypto Accelerator is a fast and energy-efficient autonomous hardware encryption and decryption accelerator. Tiny Gecko Series 1 devices support AES encryption and decryption with 128- or 256-bit keys, ECC over both GF(P) and GF(2^m), and SHA-1 and SHA-2 (SHA-224 and SHA-256).

Supported block cipher modes of operation for AES include: ECB, CTR, CBC, PCBC, CFB, OFB, GCM, CBC-MAC, GMAC and CCM.

Supported ECC NIST recommended curves include P-192, P-224, P-256, K-163, K-233, B-163 and B-233.

The CRYPTO module allows fast processing of GCM (AES), ECC and SHA with little CPU intervention. CRYPTO also provides trigger signals for DMA read and write operations.

3.7.3 True Random Number Generator (TRNG)

The TRNG module is a non-deterministic random number generator based on a full hardware solution. The TRNG is validated with NIST800-22 and AIS-31 test suites as well as being suitable for FIPS 140-2 certification (for the purposes of cryptographic key generation).

3.7.4 Security Management Unit (SMU)

The Security Management Unit (SMU) allows software to set up fine-grained security for peripheral access, which is not possible in the Memory Protection Unit (MPU). Peripherals may be secured by hardware on an individual basis, such that only priveleged accesses to the peripheral's register interface will be allowed. When an access fault occurs, the SMU reports the specific peripheral involved and can optionally generate an interrupt.

3.8 Analog

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit

Note:

1. The minimum voltage required in bypass mode is calculated using R_{BYP} from the DCDC specification table. Requirements for other loads can be calculated as $V_{DVDD\_min}+I_{LOAD} * R_{BYP\_max}$.
2. VREGVDD must be tied to AVDD. Both VREGVDD and AVDD minimum voltages must be satisfied for the part to operate.
3. The system designer should consult the characteristic specs of the capacitor used on DECOUPLE to ensure its capacitance value stays within the specified bounds across temperature and DC bias.
4. VSCALE0 to VSCALE2 voltage change transitions occur at a rate of 10 mV / usec for approximately 20 usec. During this transition, peak currents will be dependent on the value of the DECOUPLE output capacitor, from 35 mA (with a 1 µF capacitor) to 70 mA (with a 2.7 µF capacitor).
5. When the CSEN peripheral is used with chopping enabled (CSEN_CTRL_CHOPEN = ENABLE), IOVDD must be equal to AVDD.
6. The maximum limit on T_A may be lower due to device self-heating, which depends on the power dissipation of the specific application. T_A (max) = T_J (max) - ($THETA_{JA}$ x PowerDissipation). Refer to the Absolute Maximum Ratings table and the Thermal Characteristics table for T_J and $THETA_{JA}$.

4.1.3 Thermal Characteristics

Table 4.3. Thermal Characteristics

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal resistance, QFN32 Package	$THETA_{JA\_QFN32}$	4-Layer PCB, Air velocity = 0 m/s	—	25.7	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	23.2	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	21.3	—	°C/W
Thermal resistance, TQFP48 Package	$THETA_{JA\_TQFP48}$	4-Layer PCB, Air velocity = 0 m/s	—	44.1	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	43.5	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	42.3	—	°C/W
Thermal resistance, QFN64 Package	$THETA_{JA\_QFN64}$	4-Layer PCB, Air velocity = 0 m/s	—	20.9	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	18.2	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	16.4	—	°C/W
Thermal resistance, TQFP64 Package	$THETA_{JA\_TQFP64}$	4-Layer PCB, Air velocity = 0 m/s	—	37.3	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	35.6	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	33.8	—	°C/W
Thermal resistance, QFN80 Package	$THETA_{JA\_QFN80}$	4-Layer PCB, Air velocity = 0 m/s	—	20.9	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	18.2	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	16.4	—	°C/W
Thermal resistance, TQFP80 Package	$THETA_{JA\_TQFP80}$	4-Layer PCB, Air velocity = 0 m/s	—	49.3	—	°C/W
		4-Layer PCB, Air velocity = 1 m/s	—	44.5	—	°C/W
		4-Layer PCB, Air velocity = 2 m/s	—	42.6	—	°C/W

4.1.8 Brown Out Detector (BOD)

Table 4.10. Brown Out Detector (BOD)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
DVDD BOD threshold	$V_{DVDDBOD}$	DVDD rising	—	—	TBD	V
		DVDD falling (EM0/EM1)	TBD	—	—	V
		DVDD falling (EM2/EM3)	TBD	—	—	V
DVDD BOD hysteresis	$V_{DVDDBOD\_HYST}$		—	18	—	mV
DVDD BOD response time	$t_{DVDDBOD\_DELAY}$	Supply drops at 0.1V/µs rate	—	2.4	—	µs
AVDD BOD threshold	$V_{AVDDBOD}$	AVDD rising	—	—	TBD	V
		AVDD falling (EM0/EM1)	TBD	—	—	V
		AVDD falling (EM2/EM3)	TBD	—	—	V
AVDD BOD hysteresis	$V_{AVDDBOD\_HYST}$		—	20	—	mV
AVDD BOD response time	$t_{AVDDBOD\_DELAY}$	Supply drops at 0.1V/µs rate	—	2.4	—	µs
EM4 BOD threshold	$V_{EM4DBOD}$	AVDD rising	—	—	TBD	V
		AVDD falling	TBD	—	—	V
EM4 BOD hysteresis	V_{EM4BOD_HYST}		—	25	—	mV
EM4 BOD response time	t_{EM4BOD_DELAY}	Supply drops at 0.1V/µs rate	—	300	—	µs

4.1.11 General-Purpose I/O (GPIO)

Table 4.18. General-Purpose I/O (GPIO)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input low voltage	V_{IL}	GPIO pins	—	—	IOVDD*0.3	V
Input high voltage	V_{IH}	GPIO pins	IOVDD*0.7	—	—	V
Output high voltage relative to IOVDD	V_{OH}	Sourcing 3 mA, IOVDD ≥ 3 V, DRIVESTRENGTH[1] = WEAK	IOVDD*0.8	—	—	V
		Sourcing 1.2 mA, IOVDD ≥ 1.62 V, DRIVESTRENGTH[1] = WEAK	IOVDD*0.6	—	—	V
		Sourcing 20 mA, IOVDD ≥ 3 V, DRIVESTRENGTH[1] = STRONG	IOVDD*0.8	—	—	V
		Sourcing 8 mA, IOVDD ≥ 1.62 V, DRIVESTRENGTH[1] = STRONG	IOVDD*0.6	—	—	V
Output low voltage relative to IOVDD	V_{OL}	Sinking 3 mA, IOVDD ≥ 3 V, DRIVESTRENGTH[1] = WEAK	—	—	IOVDD*0.2	V
		Sinking 1.2 mA, IOVDD ≥ 1.62 V, DRIVESTRENGTH[1] = WEAK	—	—	IOVDD*0.4	V
		Sinking 20 mA, IOVDD ≥ 3 V, DRIVESTRENGTH[1] = STRONG	—	—	IOVDD*0.2	V
		Sinking 8 mA, IOVDD ≥ 1.62 V, DRIVESTRENGTH[1] = STRONG	—	—	IOVDD*0.4	V
Input leakage current	I_{IOLEAK}	All GPIO except LFXO pins, GPIO ≤ IOVDD, T ≤ 85 °C	—	0.1	TBD	nA
		LFXO Pins, GPIO ≤ IOVDD, T ≤ 85 °C	—	0.1	TBD	nA
		All GPIO except LFXO pins, GPIO ≤ IOVDD, T > 85 °C	—	—	TBD	nA
		LFXO Pins, GPIO ≤ IOVDD, T > 85 °C	—	—	TBD	nA
Input leakage current on 5VTOL pads above IOVDD	$I_{5VTOLLEAK}$	IOVDD < GPIO ≤ IOVDD + 2 V	—	3.3	TBD	µA
I/O pin pull-up/pull-down resistor	R_{PUD}		TBD	40	TBD	kΩ
Pulse width of pulses removed by the glitch suppression filter	$t_{IOGLITCH}$		TBD	25	TBD	ns

4.1.13 Analog to Digital Converter (ADC)

Specified at 1 Msps, ADCCLK = 16 MHz, BIASPROG = 0, GPBIASACC = 0, unless otherwise indicated.

Table 4.20. Analog to Digital Converter (ADC)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	$V_{RESOLUTION}$		6	—	12	Bits
Input voltage range[5]	V_{ADCIN}	Single ended	—	—	V_{FS}	V
		Differential	$-V_{FS}/2$	—	$V_{FS}/2$	V
Input range of external reference voltage, single ended and differential	$V_{ADCREFIN\_P}$		1	—	V_{AVDD}	V
Power supply rejection[2]	$PSRR_{ADC}$	At DC	—	80	—	dB
Analog input common mode rejection ratio	$CMRR_{ADC}$	At DC	—	80	—	dB
Current from all supplies, using internal reference buffer. Continous operation. WARMUPMODE[4] = KEEPADCWARM	$I_{ADC\_CONTINOUS\_LP}$	1 Msps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 1 [3]	—	270	TBD	µA
		250 ksps / 4 MHz ADCCLK, BIASPROG = 6, GPBIASACC = 1 [3]	—	125	—	µA
		62.5 ksps / 1 MHz ADCCLK, BIASPROG = 15, GPBIASACC = 1 [3]	—	80	—	µA
Current from all supplies, using internal reference buffer. Duty-cycled operation. WARMUPMODE[4] = NORMAL	$I_{ADC\_NORMAL\_LP}$	35 ksps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 1 [3]	—	45	—	µA
		5 ksps / 16 MHz ADCCLK BIASPROG = 0, GPBIASACC = 1 [3]	—	8	—	µA
Current from all supplies, using internal reference buffer. Duty-cycled operation. AWARMUPMODE[4] = KEEPINSTANDBY or KEEPINSLOWACC	$I_{ADC\_STANDBY\_LP}$	125 ksps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 1 [3]	—	105	—	µA
		35 ksps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 1 [3]	—	70	—	µA
Current from all supplies, using internal reference buffer. Continous operation. WARMUPMODE[4] = KEEPADCWARM	$I_{ADC\_CONTINOUS\_HP}$	1 Msps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 0 [3]	—	325	—	µA
		250 ksps / 4 MHz ADCCLK, BIASPROG = 6, GPBIASACC = 0 [3]	—	175	—	µA
		62.5 ksps / 1 MHz ADCCLK, BIASPROG = 15, GPBIASACC = 0 [3]	—	125	—	µA
Current from all supplies, using internal reference buffer. Duty-cycled operation. WARMUPMODE[4] = NORMAL	$I_{ADC\_NORMAL\_HP}$	35 ksps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 0 [3]	—	85	—	µA
		5 ksps / 16 MHz ADCCLK BIASPROG = 0, GPBIASACC = 0 [3]	—	16	—	µA
Current from all supplies, using internal reference buffer. Duty-cycled operation. AWARMUPMODE[4] = KEEPINSTANDBY or KEEPINSLOWACC	$I_{ADC\_STANDBY\_HP}$	125 ksps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 0 [3]	—	160	—	µA
		35 ksps / 16 MHz ADCCLK, BIASPROG = 0, GPBIASACC = 0 [3]	—	125	—	µA
Current from HFPERCLK	I_{ADC_CLK}	HFPERCLK = 16 MHz	—	166	—	µA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit

Note:

1. ACMPVDD is a supply chosen by the setting in ACMPn_CTRL_PWRSEL and may be IOVDD, AVDD or DVDD.
2. The total ACMP current is the sum of the contributions from the ACMP and its internal voltage reference. $I_{ACMPTOTAL} = I_{ACMP} + I_{ACMPREF}$.
3. ± 100 mV differential drive.
4. In ACMPn_CTRL register.
5. In ACMPn_HYSTERESIS registers.
6. In ACMPn_INPUTSEL register.

4.1.16 Capacitive Sense (CSEN)

Table 4.23. Capacitive Sense (CSEN)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Single conversion time (1x accumulation)	t_{CNV}	12-bit SAR Conversions	—	20.2	—	µs
		16-bit SAR Conversions	—	26.4	—	µs
		Delta Modulation Conversion (single comparison)	—	1.55	—	µs
Maximum external capacitive load	C_{EXTMAX}	CS0CG=7 (Gain = 1x), including routing parasitics	—	68	—	pF
		CS0CG=0 (Gain = 10x), including routing parasitics	—	680	—	pF
Maximum external series impedance	R_{EXTMAX}		—	1	—	kΩ
Supply current, EM2 bonded conversions, WARMUPMODE=NORMAL, WARMUPCNT=0	I_{CSEN_BOND}	12-bit SAR conversions, 20 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	326	—	nA
		Delta Modulation conversions, 20 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	226	—	nA
		12-bit SAR conversions, 200 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	33	—	nA
		Delta Modulation conversions, 200 ms conversion rate, CS0CG=7 (Gain = 1x), 10 channels bonded (total capacitance of 330 pF)[1]	—	25	—	nA
Supply current, EM2 scan conversions, WARMUPMODE=NORMAL, WARMUPCNT=0	I_{CSEN_EM2}	12-bit SAR conversions, 20 ms scan rate, CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	690	—	nA
		Delta Modulation conversions, 20 ms scan rate, 8 comparisons per sample (DMCR = 1, DMR = 2), CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	515	—	nA
		12-bit SAR conversions, 200 ms scan rate, CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	79	—	nA
		Delta Modulation conversions, 200 ms scan rate, 8 comparisons per sample (DMCR = 1, DMR = 2), CS0CG=0 (Gain = 10x), 8 samples per scan[1]	—	57	—	nA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Slew rate[5]	SR	DRIVESTRENGTH = 3, INCBW=1[3]	—	4.7	—	V/µs
		DRIVESTRENGTH = 3, INCBW=0	—	1.5	—	V/µs
		DRIVESTRENGTH = 2, INCBW=1[3]	—	1.27	—	V/µs
		DRIVESTRENGTH = 2, INCBW=0	—	0.42	—	V/µs
		DRIVESTRENGTH = 1, INCBW=1[3]	—	0.17	—	V/µs
		DRIVESTRENGTH = 1, INCBW=0	—	0.058	—	V/µs
		DRIVESTRENGTH = 0, INCBW=1[3]	—	0.044	—	V/µs
		DRIVESTRENGTH = 0, INCBW=0	—	0.015	—	V/µs
Startup time[6]	T_{START}	DRIVESTRENGTH = 2	—	—	TBD	µs
Input offset voltage	V_{OSI}	DRIVESTRENGTH = 2 or 3, T = 25 °C	TBD	—	TBD	mV
		DRIVESTRENGTH = 1 or 0, T = 25 °C	TBD	—	TBD	mV
		DRIVESTRENGTH = 2 or 3, across operating temperature range	TBD	—	TBD	mV
		DRIVESTRENGTH = 1 or 0, across operating temperature range	TBD	—	TBD	mV
DC power supply rejection ratio[9]	$PSRR_{DC}$	Input referred	—	70	—	dB
DC common-mode rejection ratio[9]	$CMRR_{DC}$	Input referred	—	70	—	dB
Total harmonic distortion	THD_{OPA}	DRIVESTRENGTH = 2, 3x Gain connection, 1 kHz, V_{OUT} = 0.1 V to V_{OPA} - 0.1 V	—	90	—	dB
		DRIVESTRENGTH = 0, 3x Gain connection, 0.1 kHz, V_{OUT} = 0.1 V to V_{OPA} - 0.1 V	—	90	—	dB

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit

Note:

1. Specified configuration for 3X-Gain configuration is: INCBW = 1, HCMDIS = 1, RESINSEL = VSS, V_{INPUT} = 0.5 V, V_{OUTPUT} = 1.5 V. Nominal voltage gain is 3.
2. If the maximum C_{LOAD} is exceeded, an isolation resistor is required for stability. See AN0038 for more information.
3. When INCBW is set to 1 the OPAMP bandwidth is increased. This is allowed only when the non-inverting close-loop gain is ≥ 3, or the OPAMP may not be stable.
4. Current into the load resistor is excluded. When the OPAMP is connected with closed-loop gain > 1, there will be extra current to drive the resistor feedback network. The internal resistor feedback network has total resistance of 143.5 kOhm, which will cause another ~10 µA current when the OPAMP drives 1.5 V between output and ground.
5. Step between 0.2V and V_{OPA}-0.2V, 10%-90% rising/falling range.
6. From enable to output settled. In sample-and-off mode, RC network after OPAMP will contribute extra delay. Settling error < 1mV.
7. In unit gain connection, UGF is the gain-bandwidth product of the OPAMP. In 3x Gain connection, UGF is the gain-bandwidth product of the OPAMP and 1/3 attenuation of the feedback network.
8. Specified configuration for Unit gain buffer configuration is: INCBW = 0, HCMDIS = 0, RESINSEL = DISABLE. V_{INPUT} = 0.5 V, V_{OUTPUT} = 0.5 V.
9. When HCMDIS=1 and input common mode transitions the region from V_{OPA}-1.4V to V_{OPA}-1V, input offset will change. PSRR and CMRR specifications do not apply to this transition region.

4.1.18 LCD Driver

Table 4.25. LCD Driver

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Frame rate	f_{LCDFR}		TBD	—	TBD	Hz
LCD supply range[2]	V_{LCDIN}		1.8	—	3.8	V
LCD output voltage range	V_{LCD}	Current source mode, No external LCD capacitor	2.0	—	V_{LCDIN}-0.4	V
		Step-down mode with external LCD capacitor	2.0	—	V_{LCDIN}	V
		Charge pump mode with external LCD capacitor	2.0	—	Min of 3.8 and 1.9 * V_{LCDIN}	V
Contrast control step size	$STEP_{CONTRAST}$	Current source mode	—	64	—	mV
		Charge pump or Step-down mode	—	43	—	mV
Contrast control step accuracy[1]	$ACC_{CONTRAST}$		—	+/-4	—	%

Note:

1. Step size accuracy is measured relative to the typical step size, and typ value represents one standard deviation.
2. V_{LCDIN} is selectable between the AVDD or DVDD supply pins, depending on EMU_PWRCTRL_ANASW.

4.1.22 USART SPI

SPI Master Timing

Table 4.31. SPI Master Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
SCLK period [1] [3] [2]	t_{SCLK}		2 * $t_{HFPERCLK}$	—	—	ns
CS to MOSI [1] [3]	t_{CS_MO}		-19.8	—	18.9	ns
SCLK to MOSI [1] [3]	t_{SCLK_MO}		-10	—	14.5	ns
MISO setup time [1] [3]	t_{SU_MI}	IOVDD = 1.62 V	75	—	—	ns
		IOVDD = 3.0 V	40	—	—	ns
MISO hold time [1] [3]	t_{H_MI}		-10	—	—	ns

Note:
1. Applies for both CLKPHA = 0 and CLKPHA = 1 (figure only shows CLKPHA = 0).
2. $t_{HFPERCLK}$ is one period of the selected HFPERCLK.
3. Measurement done with 8 pF output loading at 10% and 90% of V_{DD} (figure shows 50% of V_{DD}).

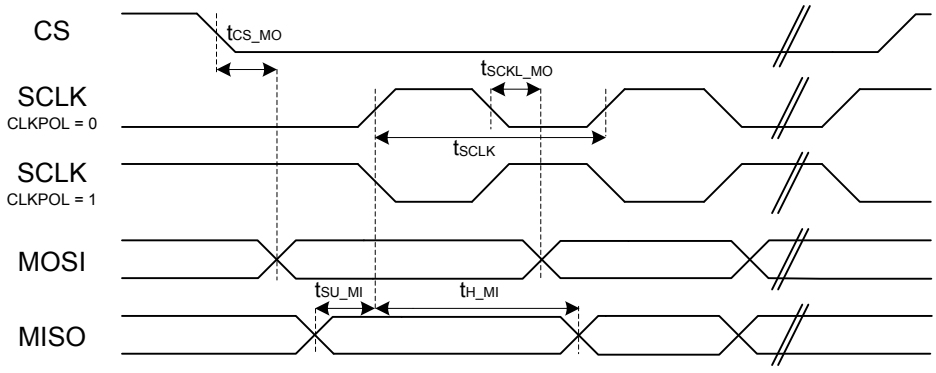

Figure 4.1. SPI Master Timing Diagram

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
VSS	9 24 51 70	Ground	PB3	10	GPIO
PB4	11	GPIO	PB5	12	GPIO
PB6	13	GPIO	PC1	14	GPIO (5V)
PC2	15	GPIO (5V)	PC3	16	GPIO (5V)
PC4	17	GPIO	PC5	18	GPIO
PB7	19	GPIO	PB8	20	GPIO
PA8	21	GPIO	PA9	22	GPIO
PA10	23	GPIO	PA12	25	GPIO
PA14	26	GPIO	RESETn	27	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
PB11	28	GPIO	PB12	29	GPIO
AVDD	30 34	Analog power supply.	PB13	31	GPIO
PB14	32	GPIO	PD0	35	GPIO (5V)
PD1	36	GPIO	PD3	37	GPIO
PD4	38	GPIO	PD5	39	GPIO
PD6	40	GPIO	PD7	41	GPIO
PD8	42	GPIO	PC6	43	GPIO
PC7	44	GPIO	VREGVSS	45	Voltage regulator VSS
VREGSW	46	DCDC regulator switching node	VREGVDD	47	Voltage regulator VDD input
DVDD	48	Digital power supply.	DECOUPLE	49	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.
PE4	52	GPIO	PE5	53	GPIO
PE6	54	GPIO	PE7	55	GPIO
PC8	56	GPIO	PC9	57	GPIO
PC10	58	GPIO (5V)	PC11	59	GPIO (5V)
PC13	60	GPIO (5V)	PC14	61	GPIO (5V)
PC15	62	GPIO (5V)	PF0	63	GPIO (5V)
PF1	64	GPIO (5V)	PF2	65	GPIO
PF3	66	GPIO	PF4	67	GPIO
PF5	68	GPIO	PE8	71	GPIO
PE9	72	GPIO	PE10	73	GPIO
PE11	74	GPIO	BODEN	75	Brown-Out Detector Enable. This pin may be left disconnected or tied to AVDD.

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PE12	76	GPIO	PE13	77	GPIO
PE14	78	GPIO	PE15	79	GPIO
PA15	80	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PE15	79	GPIO	PA15	80	GPIO

Note:

1. GPIO with 5V tolerance are indicated by (5V).

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PC4	13	GPIO	PC5	14	GPIO
PB7	15	GPIO	PB8	16	GPIO
PA12	17	GPIO	PA13	18	GPIO (5V)
PA14	19	GPIO	RESETn	20	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
PB11	21	GPIO	AVDD	23 27	Analog power supply.
PB13	24	GPIO	PB14	25	GPIO
PD0	28	GPIO (5V)	PD1	29	GPIO
PD2	30	GPIO (5V)	PD3	31	GPIO
PD4	32	GPIO	PD5	33	GPIO
PD6	34	GPIO	PD7	35	GPIO
PD8	36	GPIO	PC6	37	GPIO
PC7	38	GPIO	DVDD	39	Digital power supply.
DECOUPLE	40	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.	PE4	41	GPIO
PE5	42	GPIO	PE6	43	GPIO
PE7	44	GPIO	PC12	45	GPIO (5V)
PC13	46	GPIO (5V)	PC14	47	GPIO (5V)
PC15	48	GPIO (5V)	PF0	49	GPIO (5V)
PF1	50	GPIO (5V)	PF2	51	GPIO
PF3	52	GPIO	PF4	53	GPIO
PF5	54	GPIO	PE8	57	GPIO
PE9	58	GPIO	PE10	59	GPIO
PE11	60	GPIO	PE12	61	GPIO
PE13	62	GPIO	PE14	63	GPIO
PE15	64	GPIO			

Note:

1. GPIO with 5V tolerance are indicated by (5V).

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
PA14	8	GPIO	RESETn	9	Reset input, active low. To apply an external reset source to this pin, it is required to only drive this pin low during reset, and let the internal pull-up ensure that reset is released.
PB11	10	GPIO	AVDD	11	Analog power supply.
PB13	12	GPIO	PB14	13	GPIO
PD4	15	GPIO	PD5	16	GPIO
PD6	17	GPIO	PD7	18	GPIO
VREGSW	20	DCDC regulator switching node	VREGVDD	21	Voltage regulator VDD input
DVDD	22	Digital power supply.	DECOUPLE	23	Decouple output for on-chip voltage regulator. An external decoupling capacitor is required at this pin.
PE4	24	GPIO	PE5	25	GPIO
PC15	26	GPIO (5V)	PF0	27	GPIO (5V)
PF1	28	GPIO (5V)	PF2	29	GPIO
PE11	31	GPIO	PE12	32	GPIO

Note:

1. GPIO with 5V tolerance are indicated by (5V).

5.13 EFM32TG11B1xx in QFN32 Device Pinout

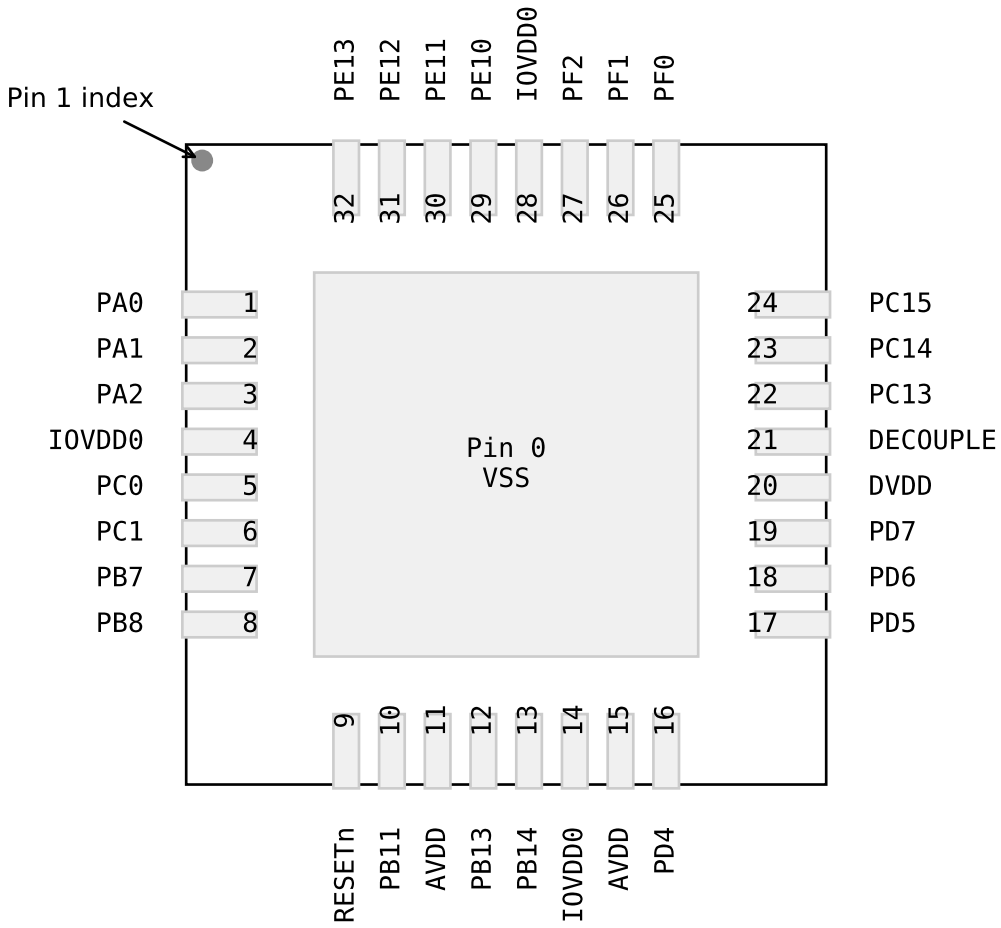

Figure 5.13. EFM32TG11B1xx in QFN32 Device Pinout

The following table provides package pin connections and general descriptions of pin functionality. For detailed information on the supported features for each GPIO pin, see 5.14 GPIO Functionality Table or 5.15 Alternate Functionality Overview.

Table 5.13. EFM32TG11B1xx in QFN32 Device Pinout

Pin Name	Pin(s)	Description	Pin Name	Pin(s)	Description
VREGVSS	0	Voltage regulator VSS	PA0	1	GPIO
PA1	2	GPIO	PA2	3	GPIO
IOVDD0	4 14 28	Digital IO power supply 0.	PC0	5	GPIO (5V)
PC1	6	GPIO (5V)	PB7	7	GPIO

Alternate	LOCATION		
Functionality	0 - 3	4 - 7	Description
VDAC0_OUT0 / OPA0_OUT	0: PB11		Digital to Analog Converter DAC0 output channel number 0.
VDAC0_OUT0ALT / OPA0_OUTALT	0: PC0 1: PC1 2: PC2 3: PC3	4: PD0	Digital to Analog Converter DAC0 alternative output for channel 0.
VDAC0_OUT1 / OPA1_OUT	0: PB12		Digital to Analog Converter DAC0 output channel number 1.
VDAC0_OUT1ALT / OPA1_OUTALT	0: PC12 1: PC13 2: PC14 3: PC15	4: PD1	Digital to Analog Converter DAC0 alternative output for channel 1.
WTIM0_CC0	0: PE4 1: PA6	4: PC15 6: PB3 7: PC1	Wide timer 0 Capture Compare input / output channel 0.
WTIM0_CC1	0: PE5	4: PF0 6: PB4 7: PC2	Wide timer 0 Capture Compare input / output channel 1.
WTIM0_CC2	0: PE6	4: PF1 6: PB5 7: PC3	Wide timer 0 Capture Compare input / output channel 2.
WTIM0_CDTI0	0: PE10 2: PA12	4: PD4	Wide timer 0 Complimentary Dead Time Insertion channel 0.
WTIM0_CDTI1	0: PE11 2: PA13	4: PD5	Wide timer 0 Complimentary Dead Time Insertion channel 1.
WTIM0_CDTI2	0: PE12 2: PA14	4: PD6	Wide timer 0 Complimentary Dead Time Insertion channel 2.
WTIM1_CC0	0: PB13 1: PD2 2: PD6 3: PC7	5: PE7	Wide timer 1 Capture Compare input / output channel 0.
WTIM1_CC1	0: PB14 1: PD3 2: PD7	4: PE4	Wide timer 1 Capture Compare input / output channel 1.
WTIM1_CC2	0: PD0 1: PD4 2: PD8	4: PE5	Wide timer 1 Capture Compare input / output channel 2.

Table 6.1. TQFP80 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.17	0.20	0.27
c	0.09	—	0.20
D	14.00 BSC		
D1	12.00 BSC		
e	0.50 BSC		
E	14.00 BSC		
E1	12.00 BSC		
L	0.45	0.60	0.75
L1	1.00 REF		
θ	0	3.5	7
aaa	0.20		
bbb	0.20		
ccc	0.08		
ddd	0.08		
eee	0.05		

Note:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This package outline conforms to JEDEC MS-026, variant ADD.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

Table 7.1. QFN80 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	—	0.05
b	0.20	0.25	0.30
A3	0.203 REF		
D	9.00 BSC		
e	0.40 BSC		
E	9.00 BSC		
D2	7.10	7.20	7.30
E2	7.10	7.20	7.30
L	0.35	0.40	0.45
aaa	0.10		
bbb	0.10		
ccc	0.10		
ddd	0.05		
eee	0.08		

Note:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.